


<b>Search Notes</b> 	<b>Application/Control No.</b> 10786900	<b>Applicant(s)/Patent Under Reexamination</b> HUANG, WEI-FENG
	<b>Examiner</b> Yeh, Eueng-nan	<b>Art Unit</b> 2624

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Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search - see search history outputs	2007/06/13	ey
PALM inventor search - see search history outputs	2007/06/13	ey
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